7th IEEE Electron Devices Technology and Manufacturing (EDTM) Conference 2023

March 7 – 10, 2023 / COEX Seoul, Korea

12E. Manufacturing Process Control	
Session Date:	March 8(Wed.), 2023
Session Time:	13:30-15:00
Session Room:	Room E (#308 a)
Session Chair:	Prof. Min Hyuk Park (Seoul National University)
	Prof. Woongkyu Lee (Soongsil University)

[12E-1] [Invited] **13:30-13:55**

Process Control Challenges and Solutions for Advanced Semiconductor Devices

Yun Jung Jee[1], Sang Hyun Han[2] and Shay Wolfling[3]

[1]Nova Measuring Instruments LTD., [2]Nova Measuring Instruments, Inc. [3]Nova LTD.

[12E-2] [Invited] **13:55-14:20**

Hybrid SPM Metrology and Defect Inspection Technologies in Advanced Process Control

ByungWoon Ahn, Ahjin Jo and Sang-Joon Cho

Park Systems Corp.

[12E-3] **14:20-14:40**

In-line SIMS Enables Better SiGe Epi Process Control for Nanosheets

Lawrence Rooney, Benjamin Hickey, Bruno Schueler, Sarah Okada and Feng Zhang

Nova Inc.

[12E-4] **14:40-15:00**

Budgeting and Predicting Pattern Defects Using Edge Placement Error and Machine Learning

Taekwon Jee[1], Joonsang You[1], Hong-Goo Lee[1], Sang-Ho Lee[1], Seungmo Hong[1], Jaewook Seo[1], Roi Meir[2], Noam Oved[2], Jun Park[2], Shin-Ik Kim[2], Byung-Jo Lim[2], Chan-Hee Kwak[2] and Jeong-Ho Yeo[2]

[1]SK hynix., [2]Applied Materials